

ABSTRACT

A chip defect detection device and detection method. The chip defect detection device comprises: a light source member (10), for transmitting a beam having at least two wavelengths; a beam splitter (40), for receiving the beam transmitted by the light source member (10), and splitting the received beam into a first part and a second part, wherein the first part of the beam is reflected by a surface to be detected of the chip (60) to form a detection beam; a reference member (70), for receiving the second part of the beam, and processing the second part of the beam to form a reference beam; a detection member (90), for receiving the detection beam and the reference beam, and forming, based on an included angle between the reference beam and the detection beam, interference lines on a detection surface of the detection member (90), and determining a defect parameter of the surface to be detected of the chip (60) according to the interference lines. The device for detecting chip defects of the present invention enhances detection accuracy and detection efficiency, and is better suited to carrying out detection on larger chip samples.